BLF8G24L-200P; **BLF8G24LS-200P**

Power LDMOS transistor

Rev. 3 — 12 July 2013

Product data sheet

1. Product profile

1.1 General description

200 W LDMOS power transistor for base station applications at frequencies from 2300 MHz to 2400 MHz.

Table 1. Typical performance

Typical RF performance at T_{case} = 25 $^{\circ}$ C in a common source class-AB production test circuit.

Test signal	f	I _{Dq}	V _{DS}	P _{L(AV)}	Gp	η_{D}	ACPR _{5M}
	(MHz)	(mA)	(V)	(W)	(dB)	(%)	(dBc)
1-carrier W-CDMA	2300 to 2400	1740	28	60	17.2	32	-37 ^[1]

^[1] Test signal: 3GPP test model 1; 64 DPCH; PAR = 7.2 dB at 0.01 % probability on CCDF.

1.2 Features and benefits

- Excellent ruggedness
- High efficiency
- Low R_{th} providing excellent thermal stability
- Designed for broadband operation (2300 MHz to 2400 MHz)
- Lower output capacitance for improved performance in Doherty applications
- Designed for low memory effects providing excellent pre-distortability
- Internally matched for ease of use
- Integrated ESD protection
- Compliant to Directive 2002/95/EC, regarding Restriction of Hazardous Substances (RoHS)

1.3 Applications

RF power amplifiers for base stations and multi carrier applications in the 2300 MHz to 2400 MHz frequency range



2. Pinning information

Table 2. Pinning

Pin Description BLF8G24L-200P (SOT539A) 1 drain1 2 drain2 3 gate1 4 gate2 5 source		
1 drain1 2 drain2 3 gate1 4 gate2	Simplified outline	Graphic symbol
2 drain2 3 gate1 4 gate2		
3 gate1 4 gate2		_
4 gate2	1 2	1
	5	3
5 source	3 4	5
	<u>[1]</u>	4
		'
		2 sym117

BLF8G2	4LS-200P (SOT539B)			
1	drain1			
2	drain2		1 2	1
3	gate1		5	,
4	gate2		3 4	3 - 5
5	source	<u>[1]</u>		4
				2 sym117

^[1] Connected to flange.

3. Ordering information

Table 3. Ordering information

Type number	Package				
	Name	Description	Version		
BLF8G24L-200P	-	flanged balanced ceramic package; 2 mounting holes; 4 leads	SOT539A		
BLF8G24LS-200P	-	earless flanged balanced ceramic package; 4 leads	SOT539B		

4. Limiting values

Table 4. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		-	65	V
V_{GS}	gate-source voltage		-0.5	+13	V
T _{stg}	storage temperature		-65	+150	°C
Tj	junction temperature		-	200	°C
T _{case}	case temperature		<u>[1]</u> -	150	°C

^[1] Continuous use at maximum temperature will affect the MTTF.

BLF8G24L-200P_LS-200P

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5. Thermal characteristics

Table 5. Thermal characteristics

Symbol	Parameter	Conditions	Тур	Unit
$R_{th(j-c)}$	thermal resistance from junction to case	T_{case} = 80 °C; P_L = 60 W	0.217	K/W

6. Characteristics

Table 6. DC characteristics

 $T_i = 25$ °C per section, unless otherwise specified.

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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$V_{(BR)DSS}$	drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 1 \text{ mA}$	65	-	-	V
$V_{GS(th)}$	gate-source threshold voltage	$V_{DS} = 10 \text{ V};$ $I_D = 100 \text{ mA}$	1.5	1.9	2.3	V
I _{DSS}	drain leakage current	$V_{GS} = 0 \text{ V}; V_{DS} = 28 \text{ V}$	-	-	2.8	μΑ
I _{DSX}	drain cut-off current	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $V_{DS} = 10 \text{ V}$	-	26.8	-	Α
I _{GSS}	gate leakage current	V_{GS} = 11 V; V_{DS} = 0 V	-	-	280	nΑ
9fs	forward transconductance	$V_{DS} = 10 \text{ V}; I_D = 5.1 \text{ A}$	-	1.2	-	S
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = V_{GS(th)} + 3.75 \text{ V};$ $I_D = 5.04 \text{ A}$	-	0.1	-	Ω

Table 7. RF characteristics

Test signal: 1-carrier W-CDMA, PAR = 7.2 dB at 0.01 % probability on the CCDF, 3GPP test model 1; 64 DPCH; f_1 = 2300 MHz; f_2 = 2400 MHz; RF performance at V_{DS} = 28 V; I_{Dq} = 1740 mA; T_{case} = 25 °C; unless otherwise specified; in a class-AB production test circuit.

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$P_{L(AV)}$	average output power		-	60	-	W
Gp	power gain		15.8	17.2	-	dB
RLin	input return loss		-	-11	-8	dB
η_{D}	drain efficiency		27	32	-	%
ACPR _{5M}	adjacent channel power ratio (5 MHz)		-	-37	-33	dBc

7. Test information

7.1 Ruggedness in class-AB operation

The BLF8G24L-200P and BLF8G24LS-200P are capable of withstanding a load mismatch corresponding to VSWR = 10 : 1 through all phases under the following conditions: $V_{DS} = 28 \text{ V}$; $I_{Dq} = 1740 \text{ mA}$; $P_{L} = 200 \text{ W}$ (CW); f = 2300 MHz.

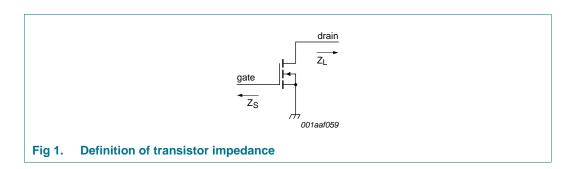
7.2 Impedance information

Table 8. Typical impedance

Measured load-pull data half section; $V_{DS} = 28 \text{ V}$; $I_{Dq} = 860 \text{ mA}$; typical values unless otherwise specified.

f	Z _S [1]	Z _L [1]
(MHz)	(Ω)	(Ω)
2300	4.24 – j6.5	1.5 – j5.4
2400	7.47 – j6.07	1.5 – j5.5

[1] Z_S and Z_L defined in Figure 1.



7.3 Test circuit

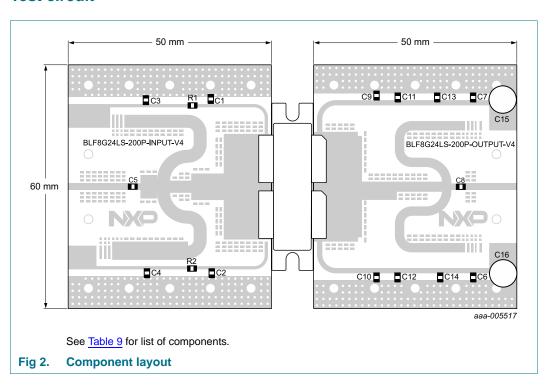


Table 9. List of components

See Figure 2 for component layout.

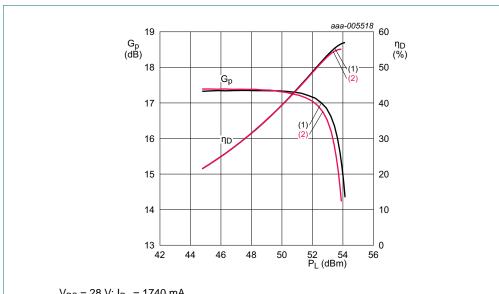
The used PCB material is Rogers RO4350B with a thickness of 0.76 mm.

Component	Description	Value	Remarks
C1, C2, C9, C10	multilayer ceramic chip capacitor	6.8 μF	<u>[1]</u>
C3, C4, C6, C7	multilayer ceramic chip capacitor	1 μF	[2]
C5, C8	multilayer ceramic chip capacitor	33 pF	<u>[1]</u>
C11, C12, C13, C14	multilayer ceramic chip capacitor	0.1 μF	[2]
C15, C16	electrolytic capacitor	1000 μF; 50 V	
R1, R2	chip resistor	5.1 Ω	<u>[3]</u>

- [1] American Technical Ceramics type 100B or capacitor of same quality.
- [2] Murata or capacitor of same quality.
- [3] Vishay Dale or resistor of same quality.

7.4 Graphical data

7.4.1 1-Tone CW

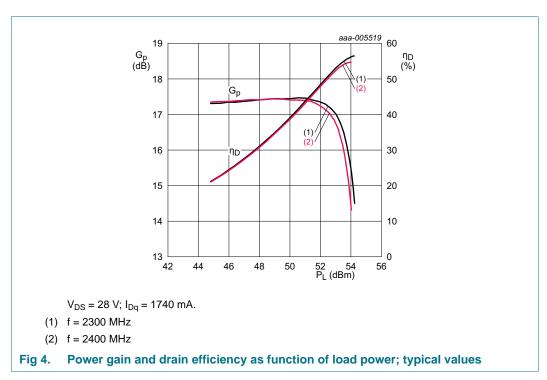


 $V_{DS} = 28 \text{ V}; I_{Dq} = 1740 \text{ mA}.$

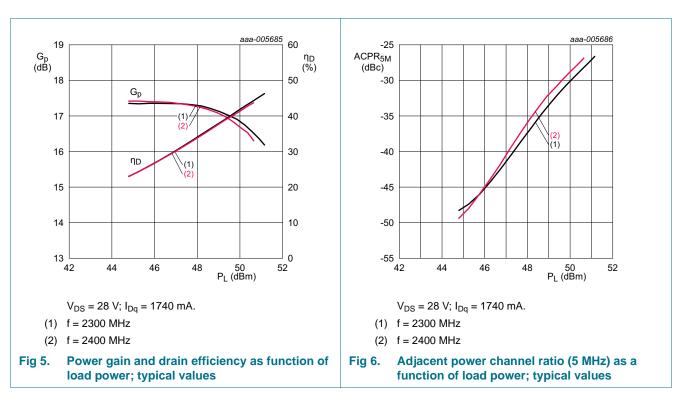
- (1) f = 2300 MHz
- (2) f = 2400 MHz

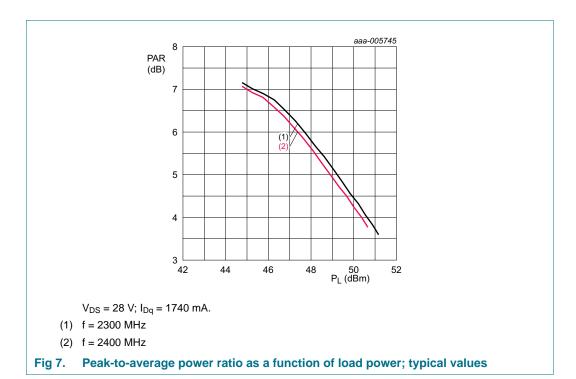
Fig 3. Power gain and drain efficiency as function of load power; typical values

7.4.2 1-Tone CW pulsed



7.4.3 1-Carrier W-CDMA





8. Package outline

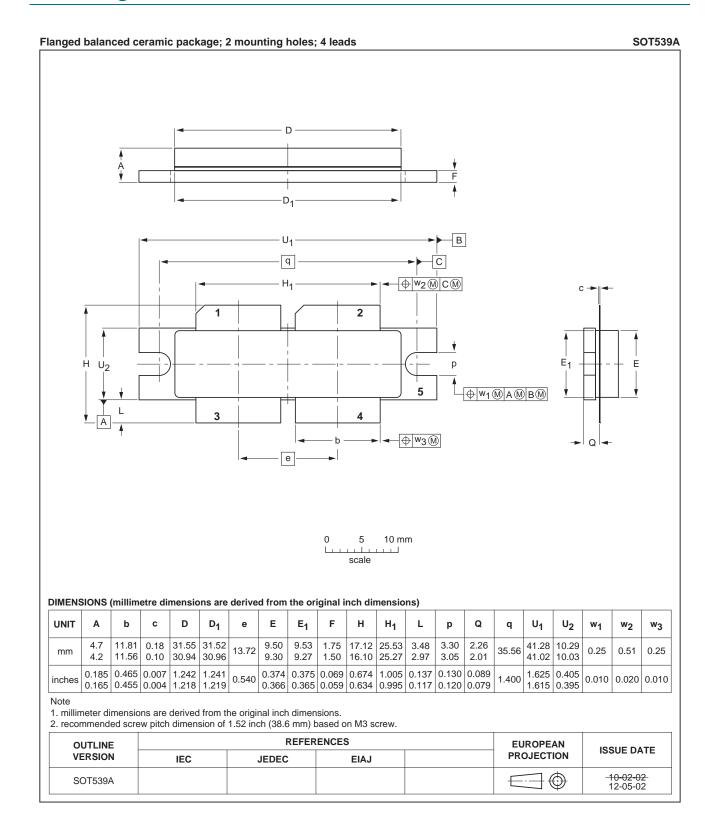


Fig 8. Package outline SOT539A

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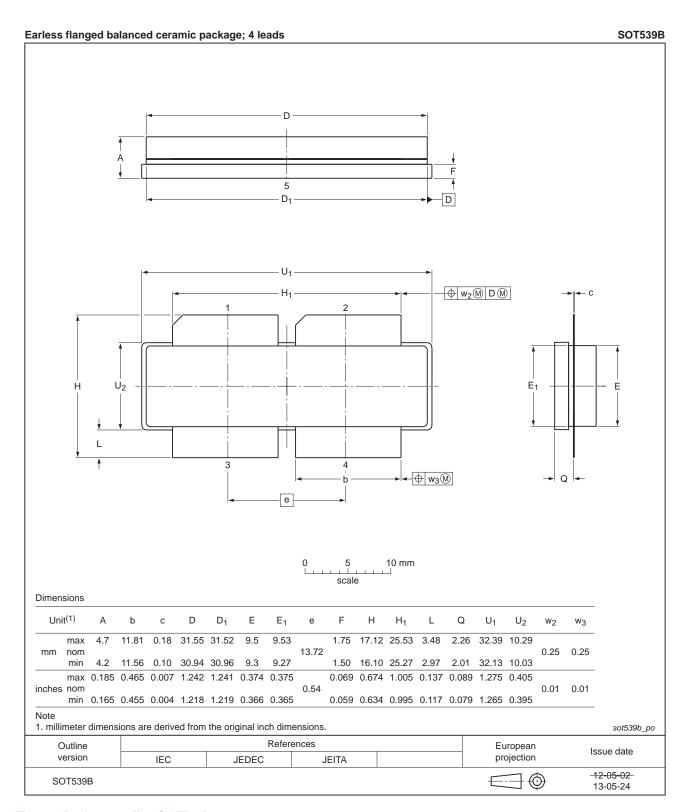


Fig 9. Package outline SOT539B

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9. Handling information

CAUTION



This device is sensitive to ElectroStatic Discharge (ESD). Observe precautions for handling electrostatic sensitive devices.

Such precautions are described in the ANSI/ESD S20.20, IEC/ST 61340-5, JESD625-A or equivalent standards.

10. Abbreviations

Table 10. Abbreviations

Acronym	Description
3GPP	3rd Generation Partnership Project
CCDF	Complementary Cumulative Distribution Function
DPCH	Dedicated Physical Channel
CW	Continuous Wave
ESD	ElectroStatic Discharge
LDMOS	Laterally Diffused Metal Oxide Semiconductor
MTTF	Mean Time To Failure
PAR	Peak-to-Average Ratio
VSWR	Voltage Standing Wave Ratio
W-CDMA	Wideband Code Division Multiple Access

11. Revision history

Table 11. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes		
BLF8G24L-200P_LS-200P v.3	20130712	Product data sheet	-	BLF8G24L-200P_LS-200P v.2		
Modifications:	 The pack 	age outline Figure 9 is	updated.			
BLF8G24L-200P_LS-200P v.2	20121203	Product data sheet	-	BLF8G24L-200P_LS-200P v.1.1		
Modifications:	 Table 1 or 	n page 1: several chang	jes.			
	 Table 4 or 	n page 2: several chang	jes.			
	 Table 5 or 	n page 3: added typical	value.			
	 Table 6 or 	n page 3: changed seve	eral values.			
	 Table 7 or 	n page 3: several chang	jes.			
	 Table 7 or 	n page 3: table moved to	o.Section 6			
	 Section 7. 	.1 on page 3: changed t	he value of I _{Dq} .			
	 Section 7. 	.2 on page 4: added sed	ction.			
	 Section 7.3 on page 4: added section. 					
	 Section 7.4 on page 5: added section. 					
	 Section 9 	on page 10: added sec	tion.			
BLF8G24L-200P_LS-200P v.1.1	20120220	Objective data sheet	-	-		

12. Legal information

12.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
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Product [short] data sheet	Production	This document contains the product specification.

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14. Contents

1	Product profile
1.1	General description 1
1.2	Features and benefits 1
1.3	Applications
2	Pinning information
3	Ordering information
4	Limiting values
5	Thermal characteristics 3
6	Characteristics
7	Test information
7.1	Ruggedness in class-AB operation 3
7.2	Impedance information 4
7.3	Test circuit 4
7.4	Graphical data 5
7.4.1	1-Tone CW
7.4.2	1-Tone CW pulsed 6
7.4.3	1-Carrier W-CDMA 6
8	Package outline 8
9	Handling information 10
10	Abbreviations
11	Revision history
12	Legal information
12.1	Data sheet status
12.2	Definitions
12.3	Disclaimers
12.4	Trademarks
13	Contact information 12
14	Contents

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